



PTO/SB/08a/b (05-03)

Approved for use through 05/31/2003. OMB 0851-0031  
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

Substitute for form 1449/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/825,486
				Filing Date	April 16, 2004
				First Named Inventor	Lee, Yun Bok
				Art Unit	2871
				Examiner Name	Tai V. Duong
Sheet	1	of	1	Attorney Docket Number	8733.1026

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	<del>6243154 B1</del>		ALREADY OF RECORD	
		<del>5977562A</del>		ALREADY OF RECORD	
TD		6433764 B1	08-2002	HEB GUCHI ET AL.	
TD		2003/0123011 A1	07-2003	CHAE	
TD		2003/0189680	10-2003	KIM ET AL.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>5</sup>
		Country Code <sup>2</sup> -Number <sup>3</sup> -Kind Code <sup>4</sup> (if known)				
	BA	<del>Japan 00-230341</del> <b>ALREADY OF RECORD</b>	<del>00-05-1987</del>	<del>Semiconductor Energy Lab Co. Ltd</del>	<del>English Abstract</del>	
TD		Japan - 2003-186017	07-03-2003	Fujitsu Display Technologies Corp	English Abstract	
TD		Japan 2000-206553	07-28-2000	Semiconductor Energy Lab Co Ltd	English Abstract	
TD		Japan - 2000-066621	03-03-2000	Semiconductor Energy Lab Co Ltd	English Abstract	
TD		Japan - 11-174482	07-02-1999	Sharp Corp	English Abstract	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 801.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	CA		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	Tai Duong	Date Considered	1/17/07
--------------------	-----------	-----------------	---------